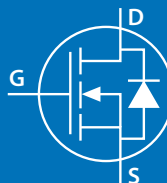


EPC2031 – Enhancement Mode Power Transistor

 V_{DS} , 60 V $R_{DS(on)}$, 2.6 m Ω I_D , 48 A

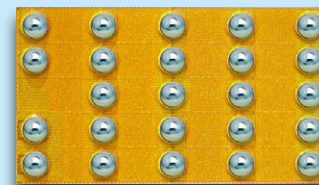
RoHS

Halogen-Free

Revised June 19, 2020

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low $R_{DS(on)}$, while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR} . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Questions:
Ask a GaN
Expert



Die size: 4.6 x 2.6 mm

EPC2031 eGaN® FETs are supplied only in passivated die form with solder bumps.

Applications

- High frequency DC-DC conversion
- Motor drive
- Industrial automation
- Synchronous rectification
- Class-D audio

Maximum Ratings			
PARAMETER		VALUE	UNIT
V_{DS}	Drain-to-Source Voltage (Continuous)	60	V
	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	72	
I_D	Continuous ($T_A = 25^\circ\text{C}$, $R_{\theta JA} = 11^\circ\text{C/W}$)	48	A
	Pulsed (25°C , $T_{PULSE} = 300 \mu\text{s}$)	450	
V_{GS}	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
T_J	Operating Temperature	-40 to 150	$^\circ\text{C}$
T_{STG}	Storage Temperature	-40 to 150	

Thermal Characteristics			
PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.45	$^\circ\text{C/W}$
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	3.9	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	45	

Note 1: $R_{\theta JA}$ is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf for details.

Static Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
BV_{DSS}	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V}$, $I_D = 1 \text{ mA}$	60			V
I_{DSS}	Drain-Source Leakage	$V_{GS} = 0 \text{ V}$, $V_{DS} = 48 \text{ V}$		0.1	0.8	mA
I_{GSS}	Gate-to-Source Forward Leakage	$V_{GS} = 5 \text{ V}$		1	9	mA
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 \text{ V}$		0.1	0.8	mA
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 15 \text{ mA}$	0.8	1.4	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}$, $I_D = 30 \text{ A}$		2	2.6	m Ω
V_{SD}	Source-Drain Forward Voltage [#]	$V_{GS} = 0 \text{ V}$, $I_S = 0.5 \text{ A}$		1.8		V

[#] Defined by design. Not subject to production test.
All measurements were done with substrate connected to source.

Scan QR code or click link below for more information including reliability reports, device models, demo boards!



<https://l.ead.me/EPC2031>

Dynamic Characteristics# (T_j = 25°C unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C _{ISS}	Input Capacitance	V _{GS} = 0 V, V _{DS} = 30 V		1640	2000	pF
C _{RSS}	Reverse Transfer Capacitance			35		
C _{OSS}	Output Capacitance			980	1500	
C _{OSS(ER)}	Effective Output Capacitance, Energy Related (Note 2)	V _{GS} = 0 V, V _{DS} = 0 to 30 V		1340		
C _{OSS(TR)}	Effective Output Capacitance, Time Related (Note 3)			1580		
R _G	Gate Resistance			0.4		Ω
Q _G	Total Gate Charge	V _{GS} = 5 V, V _{DS} = 30 V, I _D = 30 A		16	21	nC
Q _{GS}	Gate-to-Source Charge	V _{DS} = 30 V, I _D = 30 A		5		
Q _{GD}	Gate-to-Drain Charge			3.2		
Q _{G(TH)}	Gate Charge at Threshold			3.6		
Q _{OSS}	Output Charge	V _{GS} = 0 V, V _{DS} = 30 V		48	72	
Q _{RR}	Source-Drain Recovery Charge			0		

Defined by design. Not subject to production test.

All measurements were done with substrate connected to source.

Note 2: C_{OSS(ER)} is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}.

Note 3: C_{OSS(TR)} is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}.

Figure 1: Typical Output Characteristics at 25°C

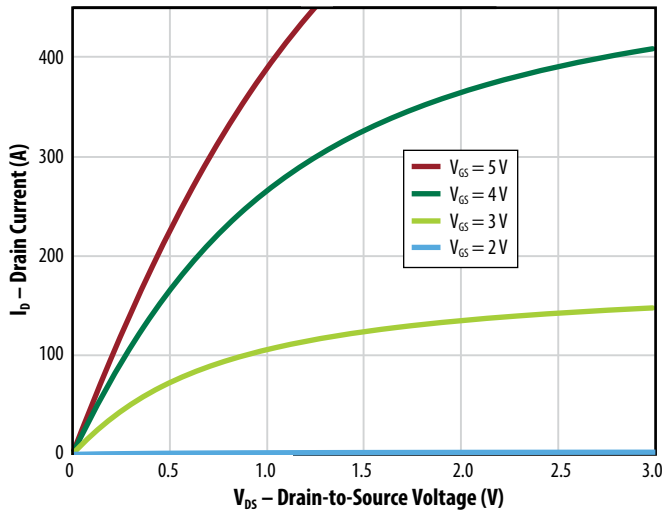


Figure 2: Typical Transfer Characteristics

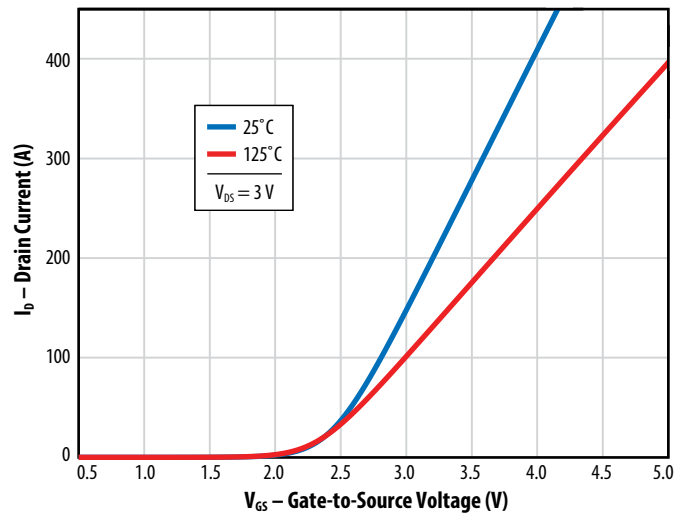


Figure 3: Typical R_{DS(on)} vs. V_{GS} for Various Drain Currents

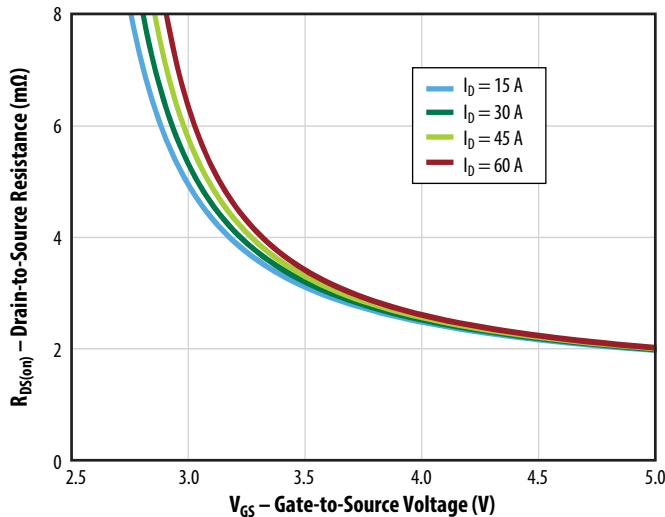


Figure 4: Typical R_{DS(on)} vs. V_{GS} for Various Temperatures

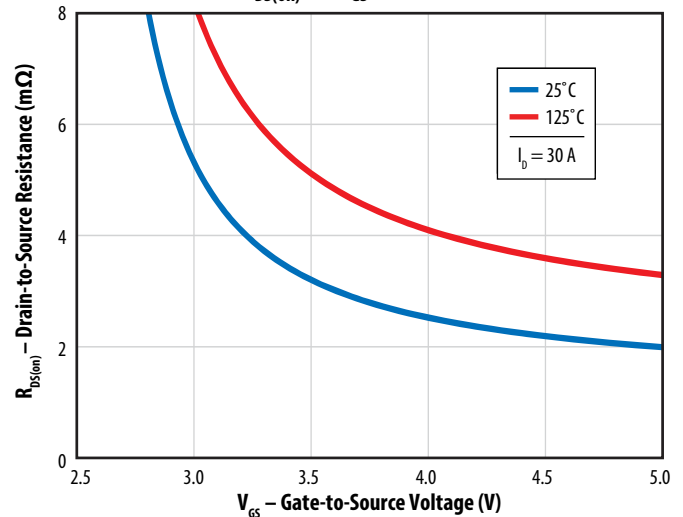


Figure 5a: Typical Capacitance (Linear Scale)

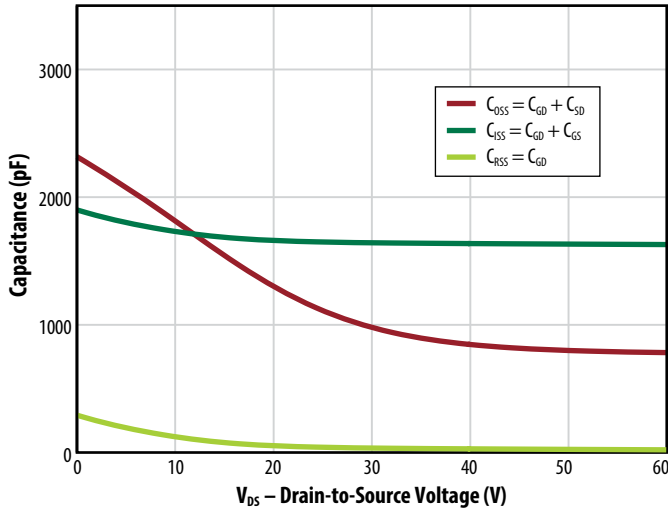


Figure 5b: Typical Capacitance (Log Scale)

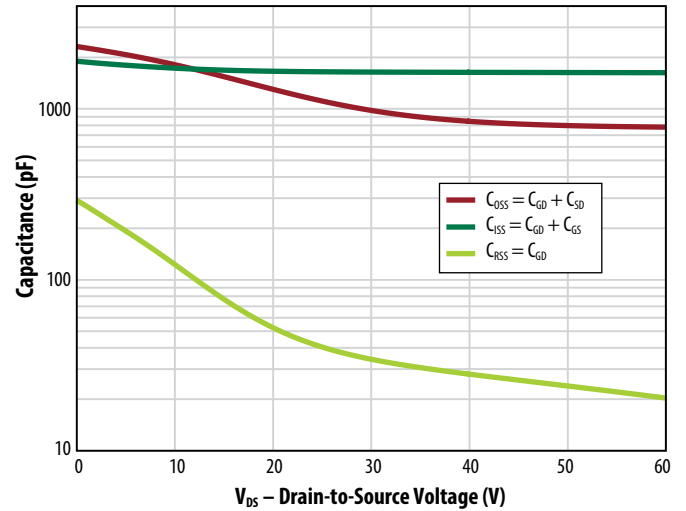


Figure 6: Typical Output Charge and C_oss Stored Energy

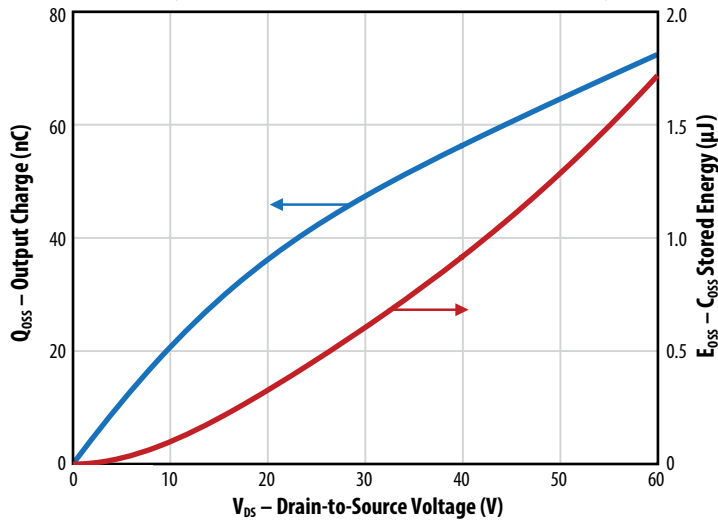


Figure 7: Typical Gate Charge

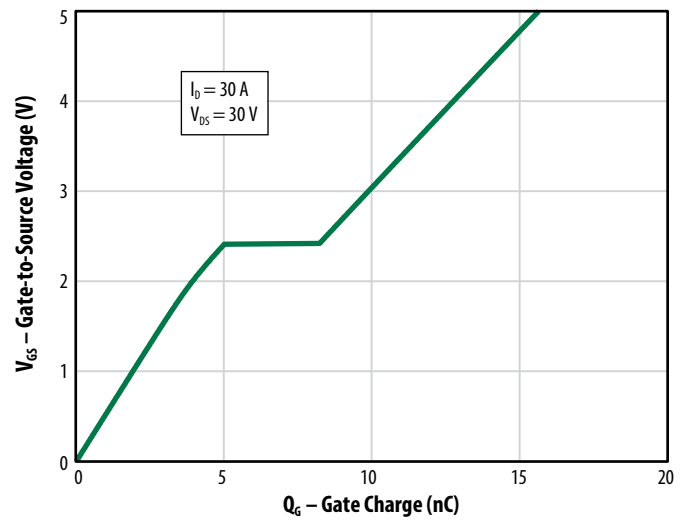


Figure 8: Typical Reverse Drain-Source Characteristics

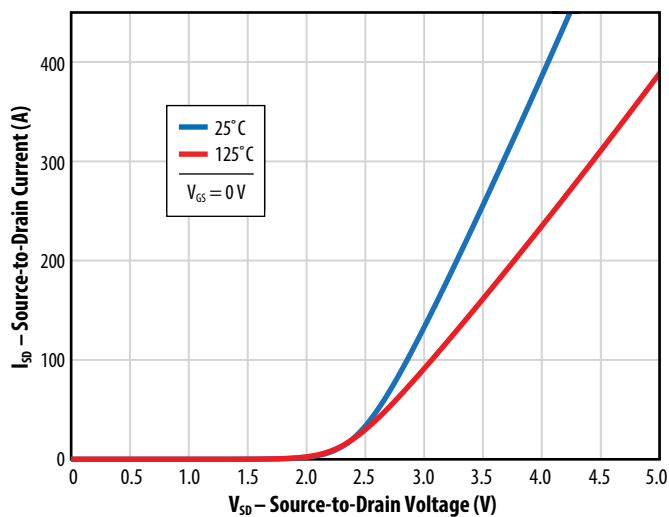
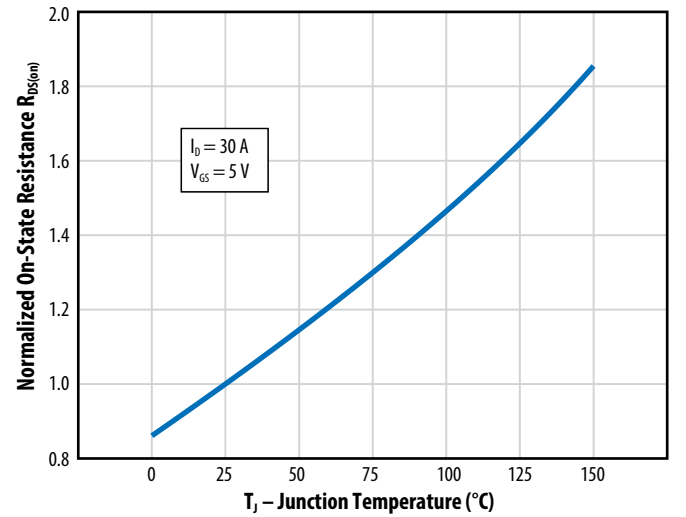


Figure 9: Typical Normalized On-State Resistance vs. Temp.



Note: Negative gate drive voltage increases the reverse drain-source voltage.
EPC recommends 0V for OFF.

Figure 10: Typical Normalized Threshold Voltage vs. Temp.

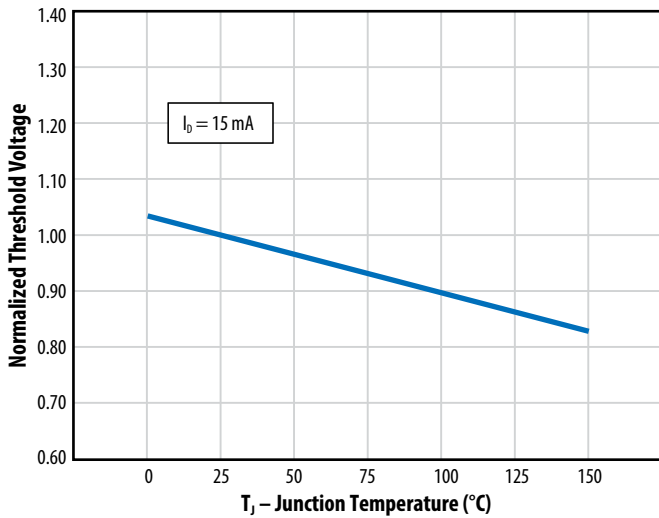


Figure 11: Safe Operating Area

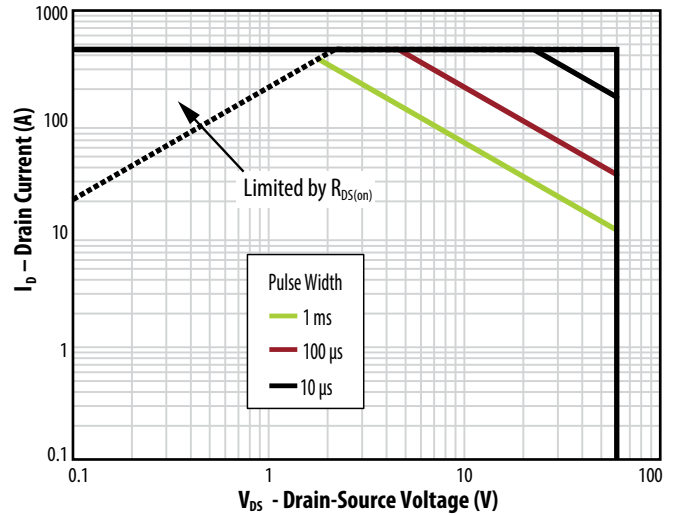
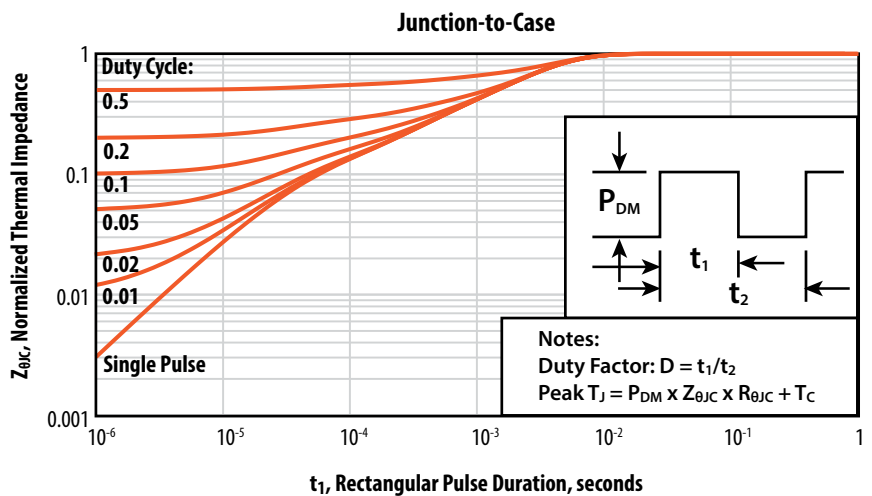
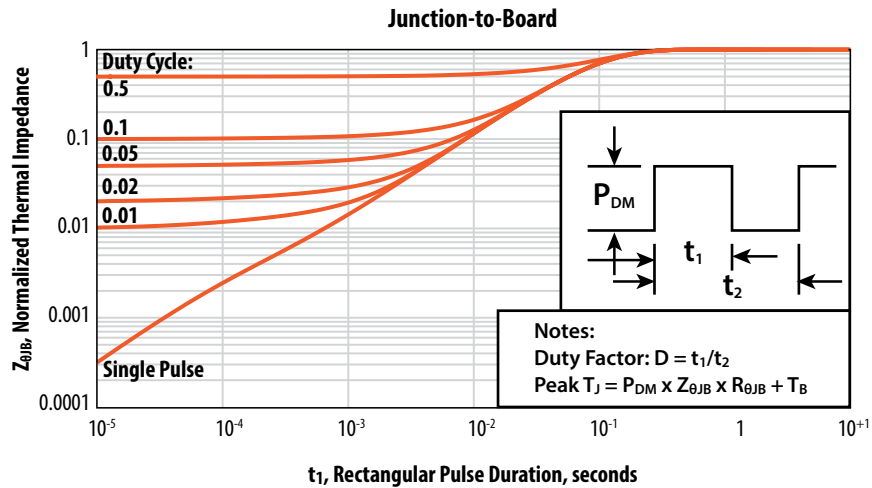
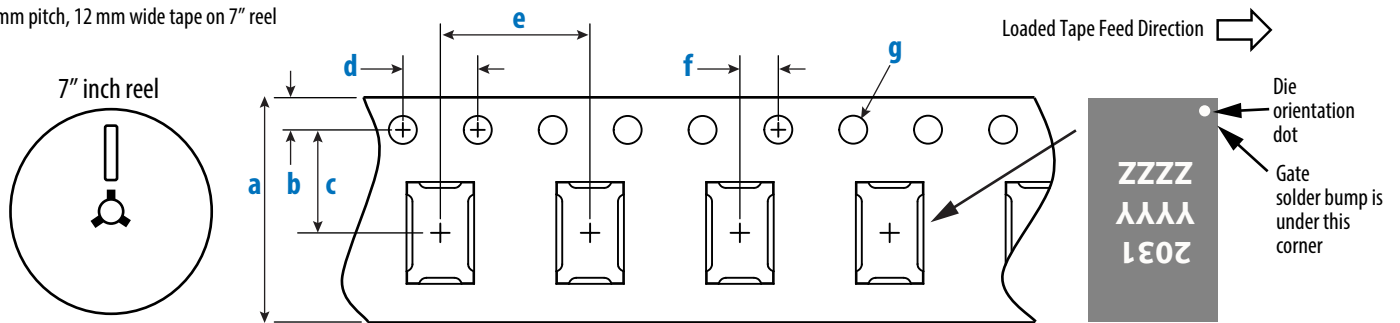


Figure 12: Typical Transient Thermal Response Curves



TAPE AND REEL CONFIGURATION

8 mm pitch, 12 mm wide tape on 7" reel



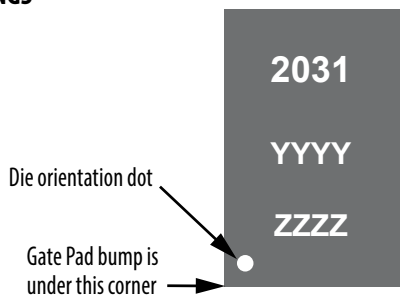
EPC2031 (Note 1)	Dimension (mm)		
	Target	MIN	MAX
a	12.00	11.90	12.30
b	1.75	1.65	1.85
c (Note 2)	5.50	5.45	5.55
d	4.00	3.90	4.10
e	8.00	7.90	8.10
f (Note 2)	2.00	1.95	2.05
g	1.50	1.50	1.60

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/ JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

Die is placed into pocket solder bump side down (face side down)

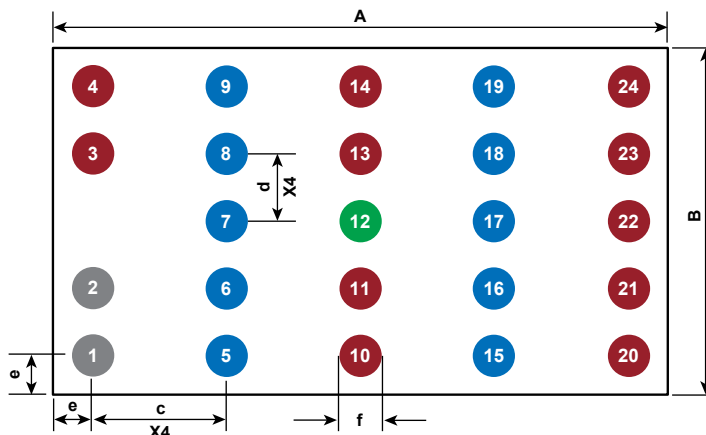
DIE MARKINGS



Part Number	Laser Markings		
	Part # Marking Line 1	Lot _Date Code Marking Line 2	Lot _Date Code Marking Line 3
EPC2031	2031	YYYY	ZZZZ

DIE OUTLINE

Solder Bump View



DIM	Micrometers		
	MIN	Nominal	MAX
A	4570	4600	4630
B	2570	2600	2630
c	1000	1000	1000
d	500	500	500
e	285	300	315
f	332	369	406

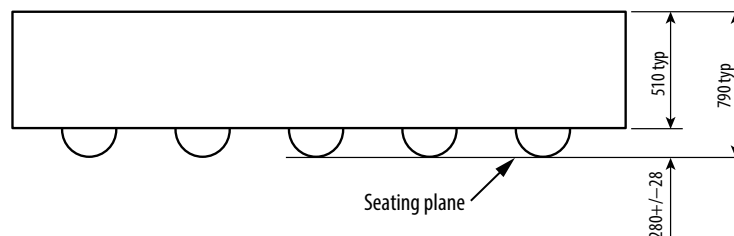
Pads 1 and 2 are Gate;

Pads 5, 6, 7, 8, 9, 15, 16, 17, 18, 19 are Drain;

Pads 3, 4, 10, 11, 13, 14, 20, 21, 22, 23, 24 are Source;

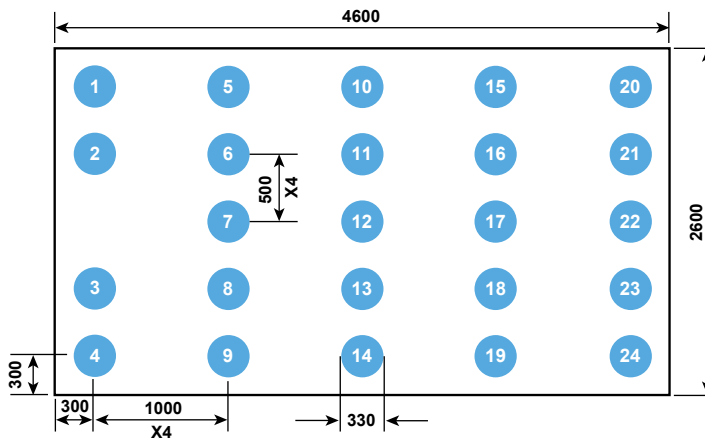
Pad 12 is Substrate*

Side View



*Substrate pin should be connected to Source

RECOMMENDED LAND PATTERN
(units in μm)



Land pattern is solder mask defined.

Pads 1 and 2 are Gate;

Pads 5, 6, 7, 8, 9, 15, 16, 17, 18, 19 are Drain;

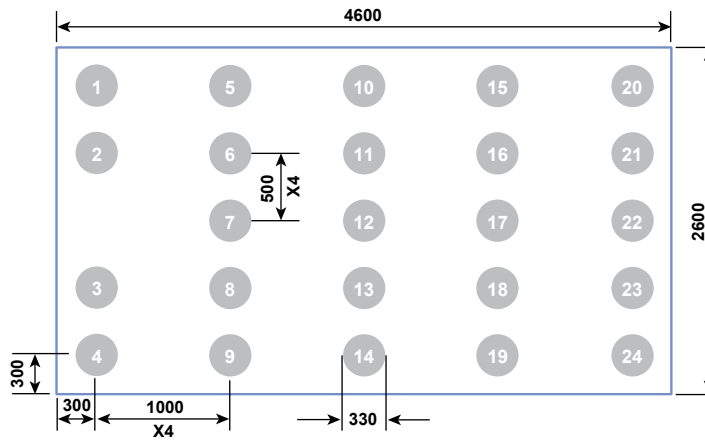
Pads 3, 4, 10, 11, 13, 14, 20, 21, 22, 23, 24 are Source;

Pad 12 is Substrate*

*Substrate pin should be connected to Source

RECOMMENDED STENCIL DRAWING
(units in μm)

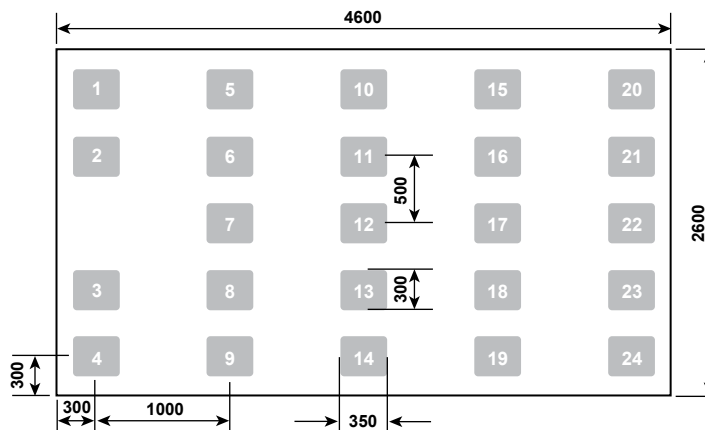
Option 1 : Intended for use with SAC305 Type 4 solder.



Recommended stencil should be 4 mil (100 μm) thick, must be laser cut, openings per drawing.

RECOMMENDED STENCIL DRAWING
(units in μm)

Option 2 : Intended for use with SAC305 Type 3 solder.



Recommended stencil should be 4 mil (100 μm) thick, must be laser cut, openings per drawing.

Additional assembly resources available at <https://epc-co.com/epc/design-support>

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